

<b>Search Notes</b>	<b>Application/Control No.</b>	<b>Applicant(s)/Patent Under Reexamination</b>
	10577919	LEE ET AL.
	<b>Examiner</b>	<b>Art Unit</b>
	MARCOS BATISTA	2617

<b>SEARCHED</b>			
<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>
370	335	5/6/2008	mb
370	342	5/6/2008	mb

<b>SEARCH NOTES</b>			
<b>Search Notes</b>	<b>Date</b>	<b>Examiner</b>	
Consulted with TA - Yogesh Aggarwal	5/6/2008	mb	
Consulted with Lun-YI Lao	5/6/2008	mb	
Inventor's Name Seach	5/6/2008	mb	
Consulted with Rafael Perez Gutierrez	5/4/2009	mb	
East Search	11/5/2008	mb	

<b>INTERFERENCE SEARCH</b>			
<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>

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